Special Session 3B: E.J. McCluskey Doctoral Thesis Award Semi-Final - Posters

Organizers: M. Portolan (Alcatel-Lucent) & M. Maniatakos (NYU-AD)
Moderator: M. Maniatakos (NYU-AD)

Named after Prof. E.J. McCluskey, a key contributor to the field of test technology, the 2013 TTTC's Doctoral Thesis Award serves the purpose to promote most impactful doctoral student work, to provide the students with the exposure to the community and the prospective employers, and to support interaction between academia and industry in the field of test technology. TTTC's E.J. McCluskey Best Doctoral Thesis Award will be given to the winning student of the doctoral student contest and his or her advisor. The award consists of a certificate, an honorarium and an invitation to submit a paper on the presented work to the IEEE Design & Test magazine.

The contest is held in two stages: semi-finals and finals: In 2013, semi-finals will be held at the IEEE VLSI Test Symposium (VTS), the IEEE European Test Symposium (ETS) and the IEEE Latin American Test Workshop (LATW). At each semi-final, a jury composed of industrial and academic experts will determine the winner, and the three winners will compete against each other in the finals, held at the International Test Conference (ITC) 2013.

In this 1-hour poster session, each contestant will present his/her doctoral thesis work to the public and the industrial jury. The poster session, along with the presentation session 8A, will be judged by the industrial experts with regards to theoretical advancement, industrial relevance and presentation. The grades submitted by the industrial panel will be combined with the grades given by the academic jury, consisting of distinguished professors. The winner will be announced during the VTS 2013 social event, to which all finalists are invited.

Contestants:
1. Prasanjeet Das (University of Southern California)
Thesis Title: A Variation Aware Resilient Framework for Post-silicon Delay Validation of High Performance Circuits
Advisor: Sandeep Gupta
2. Ke Huang (TIMA Lab)
Thesis Title: Fault Modeling and Diagnosis for Nanometric Analog/Mixed-Signal/RF Circuits
Advisors: Salvador Mir & Haralampos Stratigopoulos
3. Yanjing Li (Stanford)
Thesis Title: Online Self-Test, Diagnostics, and Self-Repair for Robust System Design
Advisor: Subhasish Mitra
4. Dzmitry Maliuk (Yale University)
Thesis Title: Analog Neural Classifiers for Built-In Self-Test of Analog/RF Circuits
Advisor: Yiorgos Makris
5. Brandon Noia (Duke University)
Thesis Title: Design-for-Test and Test Optimization of TSV-based 3D Stacked ICs
Advisor: Krishnendu Chakrabarty
6. Ender Yilmaz (Arizona State University)
Thesis Title: Efficient Test Strategies for Analog/RF Circuits
Advisor: Sule Ozev

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